

# H1M065B200

Silicon Carbide MOSFET  
N-CHANNEL ENHANCEMENT MODE

## Features

- Low On-Resistance and High Current Density
- Low Capacitance for High Frequency Operation
- Ultra-high Avalanche Ruggedness
- Positive Temperature Coefficient Device
- AEC-Q101 Qualified
- RoHS Compliant and Halogen Free

## Benefits

- Higher System Efficiency
- Increase Parallel Device Convenience
- Capable of 175°C High  $T_j$  Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems

## Applications

- Switching Mode Power Supply
- DC/DC Converters, UPS, and PFC
- EV Charging Station
- Motor Drives
- Power Inverters
- Solar/Wind Renewable Energy

## Absolute Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	$V_{DS,max}$	$V_{GS}=0V, I_{DS}=100\mu A$	650	V
Continuous Drain Current	$I_D$	$V_{GS}=20V, T_c=25^\circ\text{C}$	18.5	A
		$V_{GS}=20V, T_c=110^\circ\text{C}$	12.5	
Pulse Drain Current	$I_{D,pulse}$	$t_{PW}$ limitation per Fig.15	34.5	
Avalanche energy, Single Pulse	$E_{AS}$	$V_{DD}=100V, I_D=5A$	400	mJ
Power Dissipation	$P_D$	$T_c=25^\circ\text{C}$	102	W
Recommend Gate Source Voltage	$V_{GS,op}$	Static, recommended DC operating values	-5 to 20	V
Maximum Gate Source Voltage	$V_{GS,max}$	Transient operating limit (AC $f > 1\text{Hz}$ , duty cycle $< 1\%$ )	-10 to 25	
Junction & Storage Temperature	$T_j, T_{stg}$		-55 to 175	$^\circ\text{C}$
Soldering Temperature	$T_L$		260	
Mounting Torque	$M_D$	M3 or 6-32 screw	1.0	Nm

## Thermal Resistance

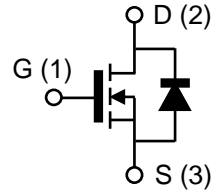
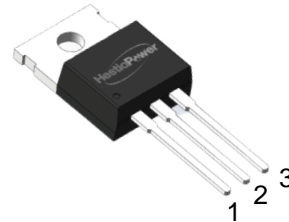
Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction to Case	$R_{\theta,JC}$		1.47		$^\circ\text{C/W}$
Thermal Resistance, Junction to Ambient	$R_{\theta,JA}$				$^\circ\text{C/W}$

## Product Summary

$V_{DS}$	650V
$I_D(@25^\circ\text{C})$	18.5A
$R_{DS(on)}$	200mΩ



## Circuit Diagram



Part Number	Package	Marking
H1M065B200	TO-220-3L	H1M065B200

## Description

The H1M065B200 650V, 200mΩ silicon carbide power MOSFET is an N-channel enhancement mode device. Exploiting the outstanding wide bandgap material properties, this device shows high current density and great switching behavior. Thanks for the excellent thermal conductivity and many advantages of SiC, this device significantly improved in thermal capability and temperature independent switching behavior. With the high stability and reliability, this device also passes the qualification criteria based on AEC-Q101.

## Electrical Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>DS</sub> =100μA	650			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =10V, I <sub>DS</sub> =5mA		2.6		V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V		<1	50	μA
		V <sub>DS</sub> =650V, V <sub>GS</sub> =0V T <sub>J</sub> =175°C		5	500	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V			250	nA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =20V, I <sub>DS</sub> =6A		200	260	mΩ
		V <sub>GS</sub> =20V, I <sub>DS</sub> =6A, T <sub>J</sub> =175°C		260		
Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =17V, I <sub>DS</sub> =15A		4.5		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V f=1MHz, V <sub>AC</sub> =25mV		498		pF
Output Capacitance	C <sub>oss</sub>			59		
Reverse Transfer Capacitance	C <sub>rss</sub>			8		
Effective Output Capacitance, Energy Related	C <sub>o(er)</sub>		V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 400V		74.5	
Effective Output Capacitance, Time Related	C <sub>o(tr)</sub>	I <sub>D</sub> =const., V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 400V		100		
Short-Circuit Withstand Time	t <sub>SC</sub>	V <sub>GS</sub> =0/15V, V <sub>DS</sub> =400V R <sub>G</sub> =100Ω		<18		μs
Turn On Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =-4/+20V, I <sub>D</sub> =5A, R <sub>L</sub> =80Ω, R <sub>G(ext)</sub> = 2.7 Ω		15		ns
Rise Time	t <sub>r</sub>			17		
Turn Off Delay Time	t <sub>d(off)</sub>			17		
Fall Time	t <sub>f</sub>			20		
C <sub>oss</sub> Stored Energy	E <sub>oss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V f=1MHz, V <sub>AC</sub> =25mV		5.7		μJ
Turn-on Switching Energy	E <sub>on</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =0/20V, I <sub>D</sub> =6A,		39.6		
Turn-off Switching Energy	E <sub>off</sub>	R <sub>G(ext)</sub> = 2.7 Ω		8.36		
Internal Gate Resistance	R <sub>G(int.)</sub>	f=1MHz, V <sub>AC</sub> =25mV		3.6		Ω

## Built-in SiC Diode Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Typ.	Unit
Inverse Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>SD</sub> =2A	3.5	V
Continuous Diode Forward Current	I <sub>S</sub>	V <sub>GS</sub> =-5V, T <sub>C</sub> =25°C	15	A
Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> =0V,	50	ns
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>SD</sub> =5A, V <sub>DS</sub> =400V,	35	nC
Peak Reverse Recovery Current	I <sub>rrm</sub>	di/dt=300A/μs	1.8	A

## Gate Charge Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Gate to Source Charge	Q <sub>GS</sub>	V <sub>DS</sub> =400V, V <sub>GS</sub> =-5/+20V, I <sub>D</sub> =5A	10	nC
Gate to Drain Charge	Q <sub>GD</sub>		19	
Total Gate Charge	Q <sub>G</sub>		43	
Gate plateau voltage	V <sub>pl</sub>		8.7	V

## Typical Device Performance

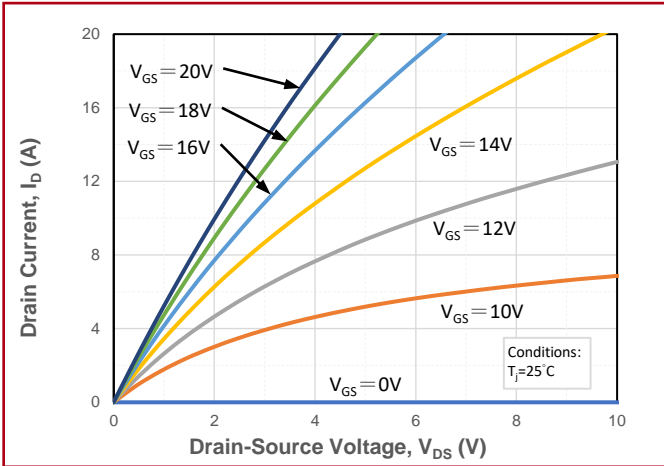


Fig.1 Forward Output Characteristics at  $T_j = 25^\circ\text{C}$

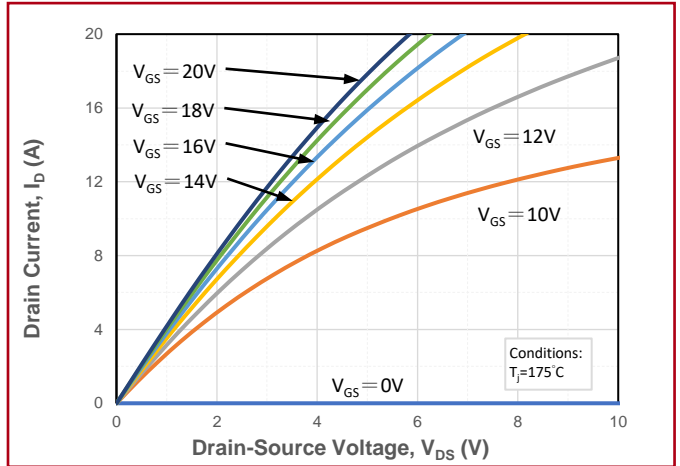


Fig.2 Forward Output Characteristics at  $T_j = 175^\circ\text{C}$

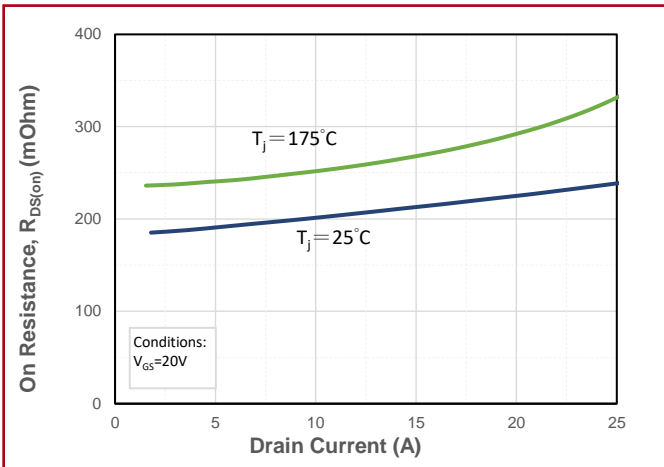


Fig.3 On-Resistance vs. Drain Current for Various  $T_j$

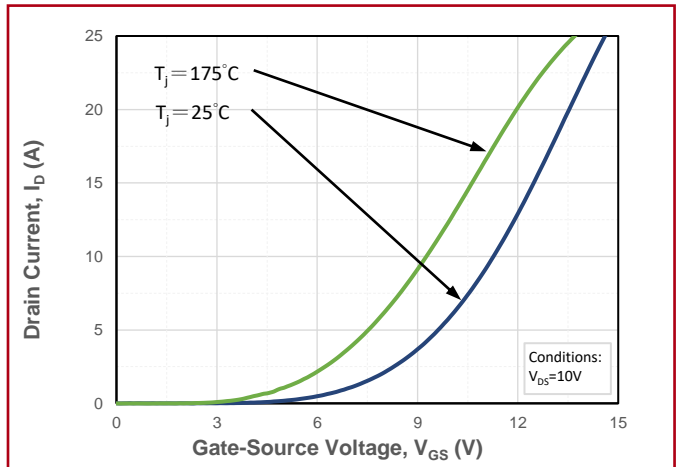


Fig.4 Transfer Characteristics for Various  $T_j$

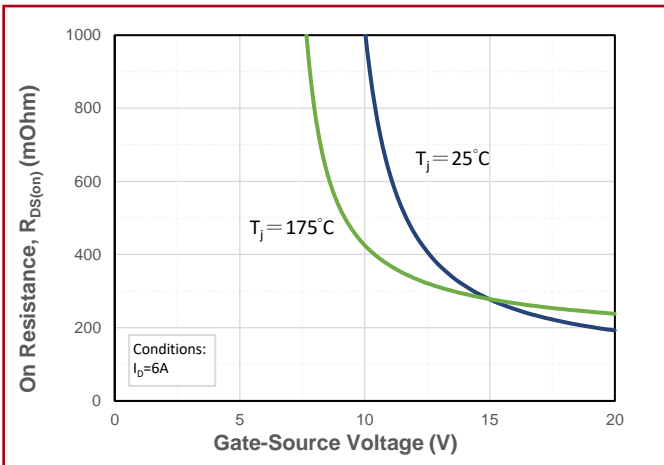


Fig.5 On-Resistance vs. Gate Voltage for Various  $T_j$

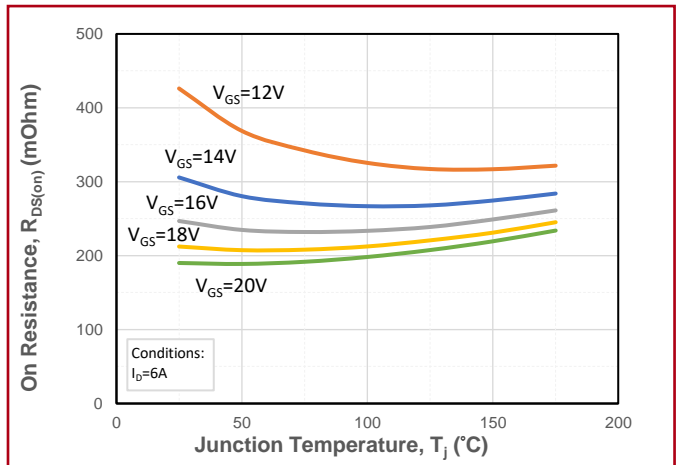
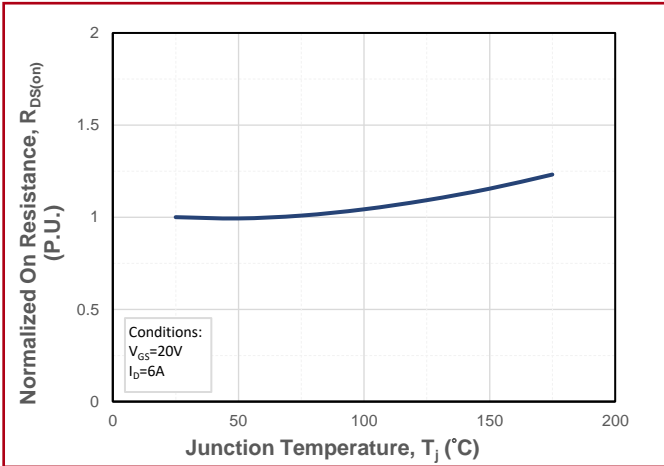
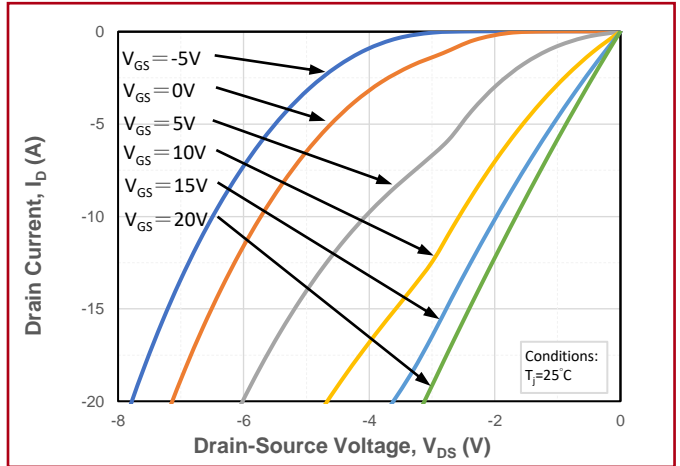


Fig.6 On-Resistance vs. Temperature for Various Gate Voltage

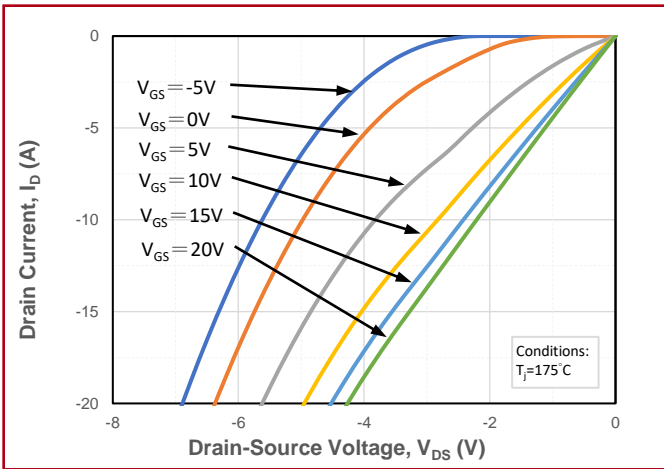
## Typical Device Performance



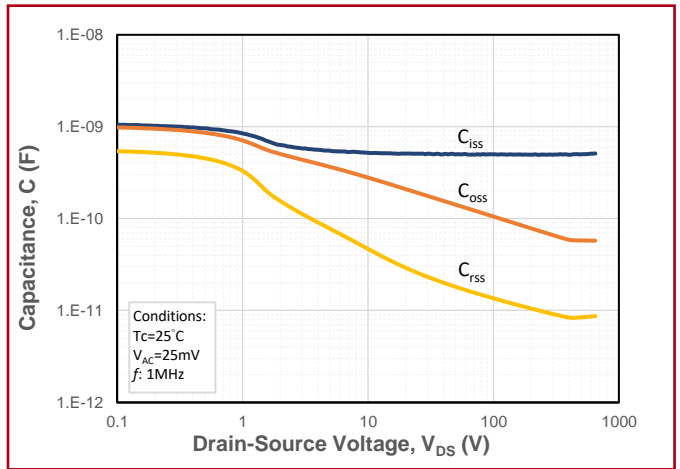
**Fig.7** Normalized On-Resistance vs. Temperature



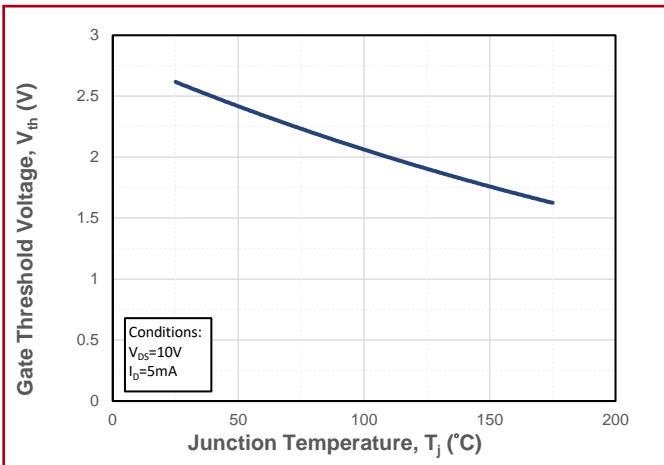
**Fig.8** Reverse Output Characteristics at  $T_j = 25^\circ C$



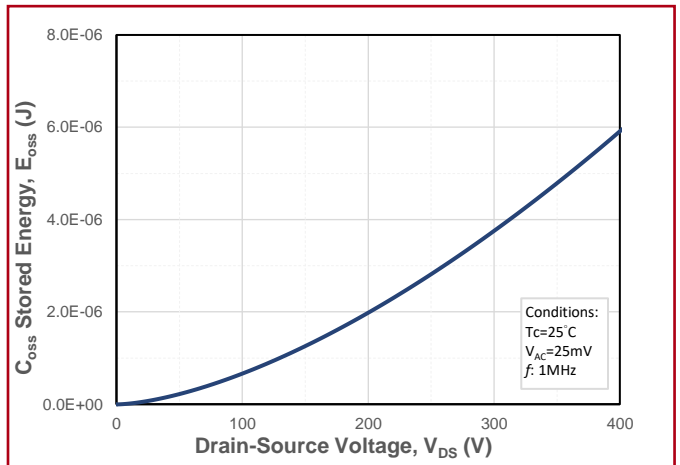
**Fig.9** Reverse Output Characteristics at  $T_j = 175^\circ C$



**Fig.10** Capacitances vs. Drain to Source Voltage

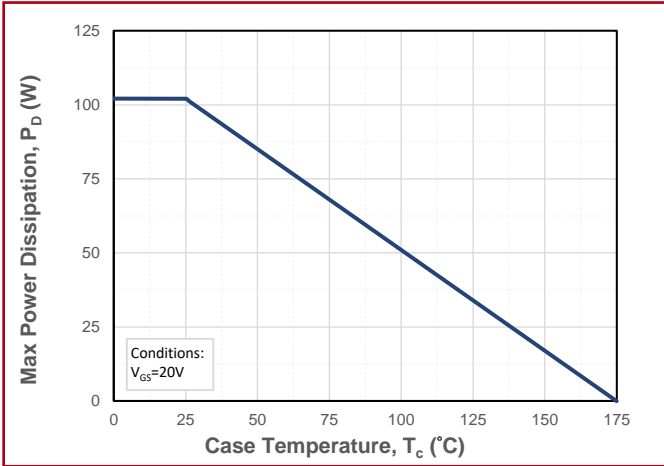


**Fig.11** Threshold Voltage vs. Temperature

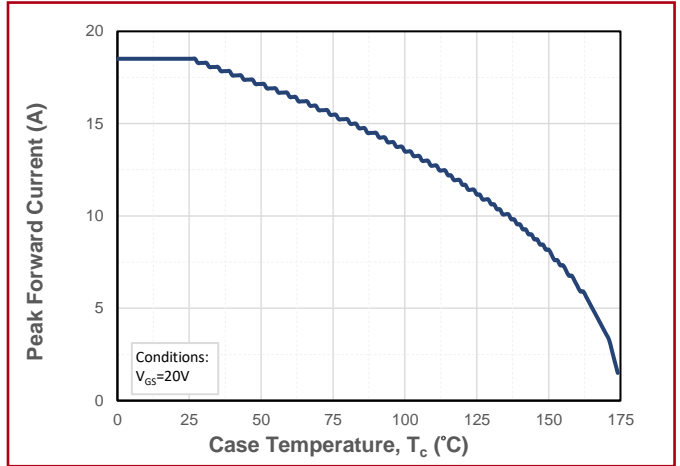


**Fig.12** Output Capacitor Stored Energy

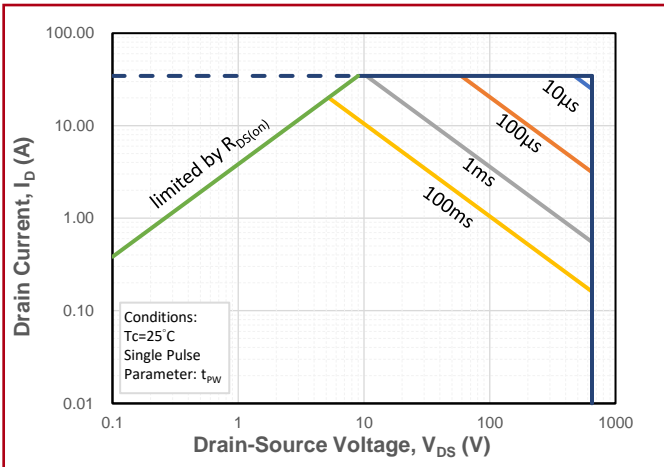
## Typical Device Performance



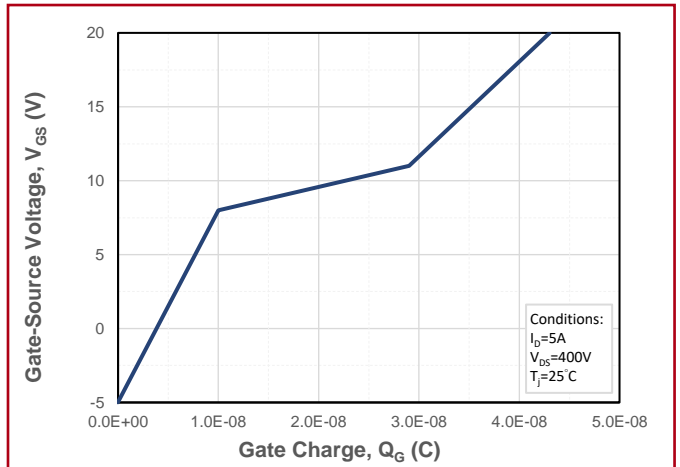
**Fig.13 Maximum Power Dissipation Derating vs. Case Temperature**



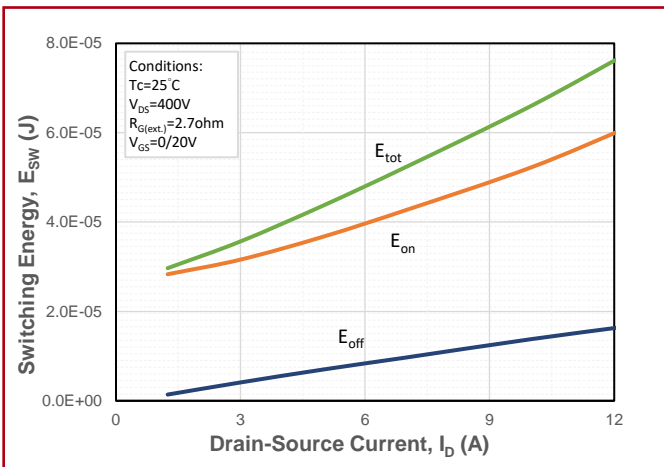
**Fig.14 Drain Current Derating vs. Case Temperature**



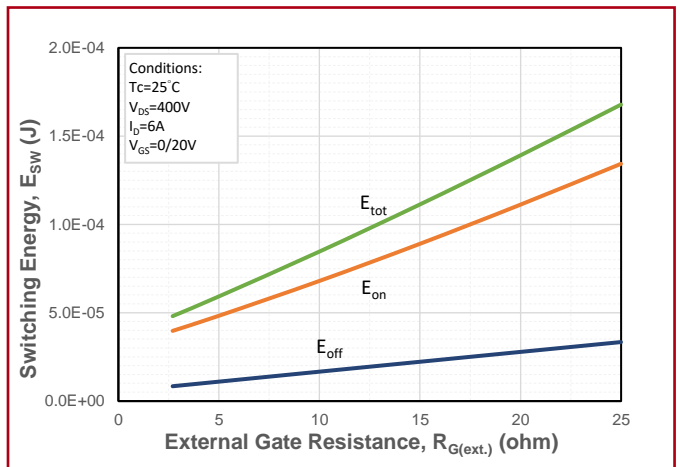
**Fig.15 Safe Operating Area**



**Fig.16 Gate Charge Characteristics**



**Fig.17 Clamped Inductive Switching Energy vs. Drain Current**



**Fig.18 Clamped Inductive Switching Energy vs. External Gate Resistor ( $R_{G(ext.)}$ )**

## Typical Device Performance

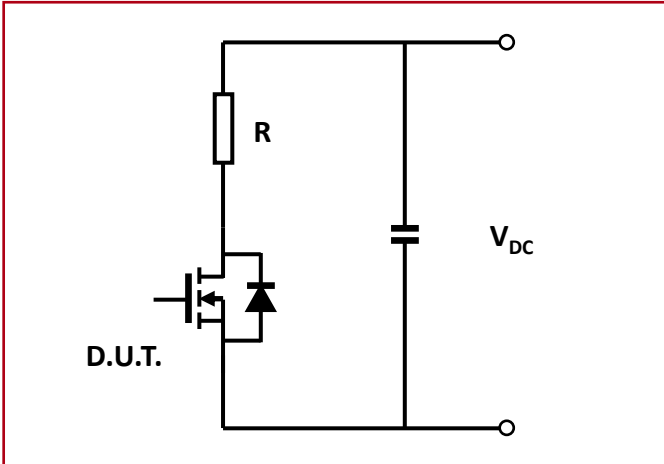


Fig.19 Schematic of Resistive Switching

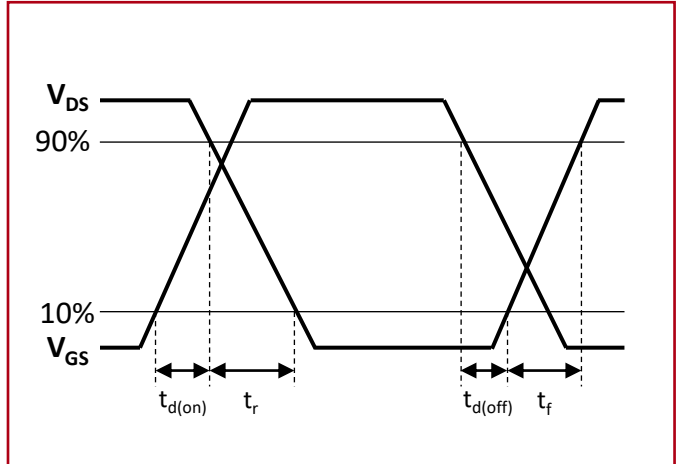


Fig.20 Switching Times Definition

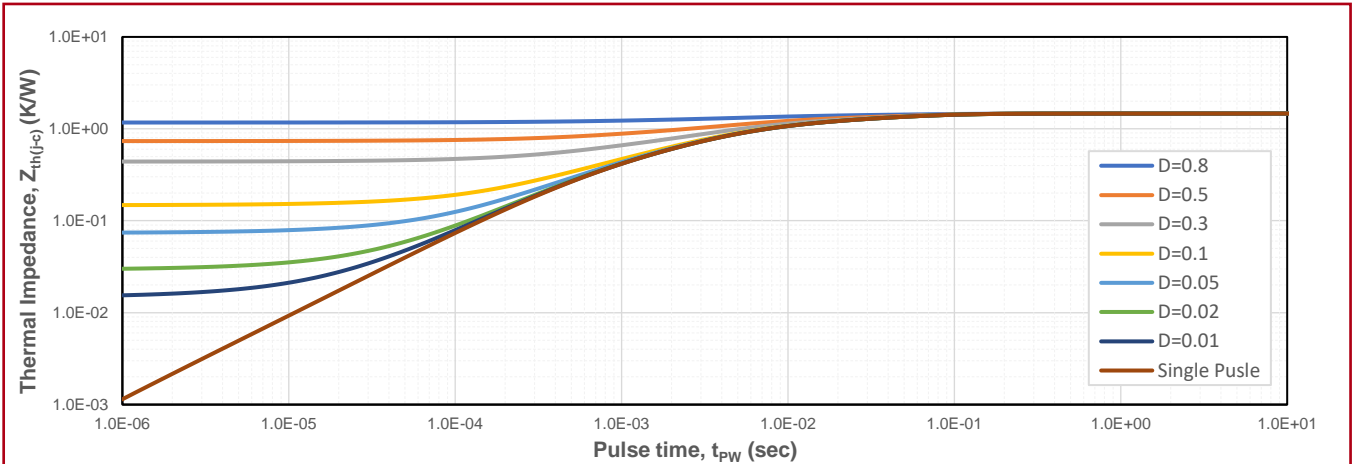


Fig.21 Transient Junction to Case Thermal Impedance

### Naming Rule

**H1 M 065 B 200**

#### Generation

H1 = Gen 1<sup>st</sup> Discrete

#### Device Type

M = MOSFET    J = JMOS

S = JBS diode

#### Breakdown Voltage

065 = 650V    170 = 1700V

120 = 1200V    330 = 3300V

#### Package

F = TO-247-3L    B = TO-220-3L

T = TO-263-2L    N = Bare Die

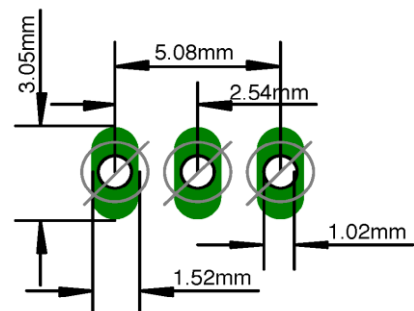
#### Typical On-Resistance

020 = 20mΩ    050 = 50mΩ    100 = 100mΩ

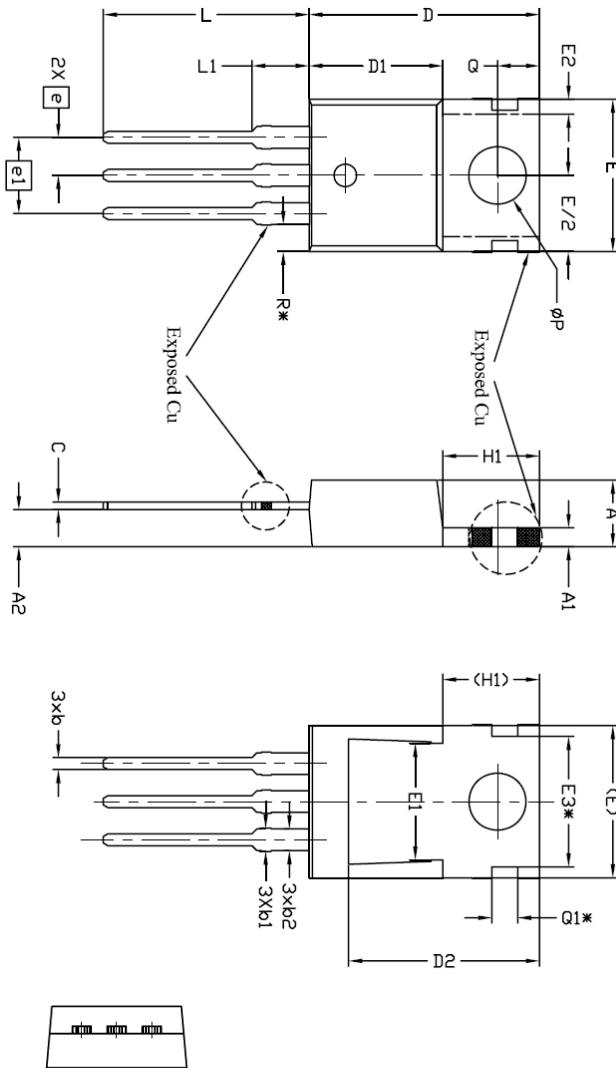
200 = 200mΩ

### Recommended Solder Pad Layout

#### TO-220-3L



## Package Dimensions



Symbol	mm			NOTES
	Min.	Typ.	Max.	
A	4,24	4,44	4,64	
A1	1,15	1,27	1,40	
A2	2,30	2,48	2,70	
b	0,70	0,80	0,90	
b1	1,20	1,55	1,75	
b2	1,20	1,45	1,70	
c	0,40	0,50	0,60	
D	14,70	15,37	16,00	4
D1	8,82	8,92	9,02	
D2	12,43	12,73	12,83	5
E	9,96	10,16	10,36	4,5
E1	6,86	7,77	8,89	5
E2	-	-	0,76	6
E3*	8,70REF.			
e	2,54BSC			
e1	5,08BSC			
H1	6,30	6,45	6,60	5,6
L	13,47	13,72	13,97	
L1	3,60	3,80	4,00	
$\phi P$	3,75	3,84	3,93	
Q	2,60	2,80	3,00	
Q1*	1,73REF.			
R*	1,82REF.			

Note:

1. Package Reference: JEDEC TO220, Variation AB.
2. All Dimensions Are In mm.
3. Slot Required, Notch May Be Rounded
4. Dimension D & E Do Not Include Mold Flash. Mold Flash Shall Not Exceed 0.127mm Pre Side. These Dimensions Are Measured At The Outermost Extreme Of The Plastic Body.
5. Thermal Pad Contour Optional Within Dimensions E, H1, D2 & E1.
6. Dimension E2 & H1 Define A Zone Where Stamping And Singulation Irregularities Are Allowed.
7. "\*" is reference .

## Notes

- The information provided herein is subject to change without notice.
- For other information that does not show on this datasheet, please contact us for inquiry.